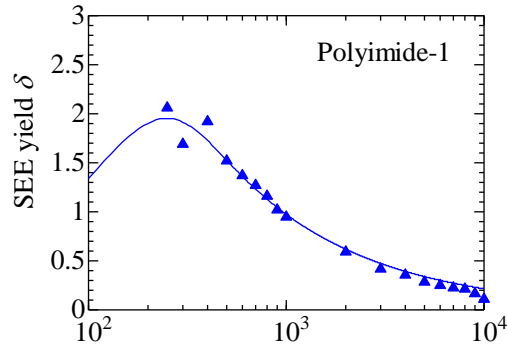
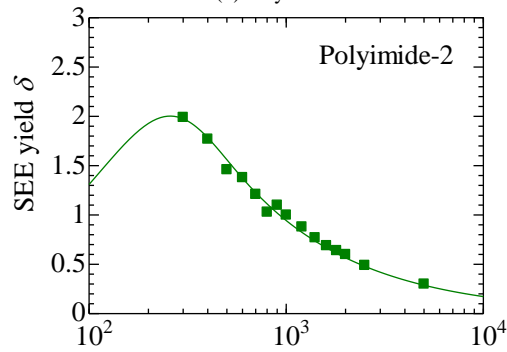


(a) FEP



(b) Polyimide-1

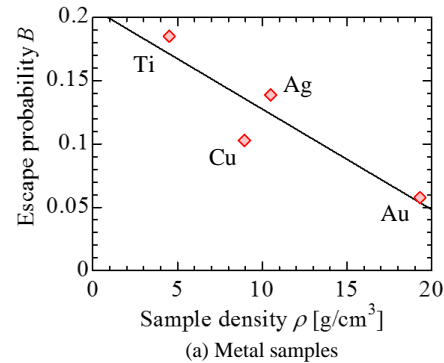


(c) Polyimide-2

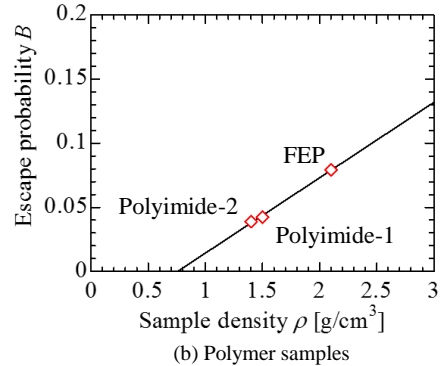
Fig. 6. The measurement results and the fitting results using Dekker's formula on polymer samples.

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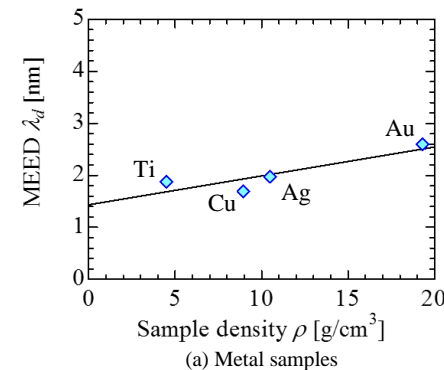


(a) Metal samples

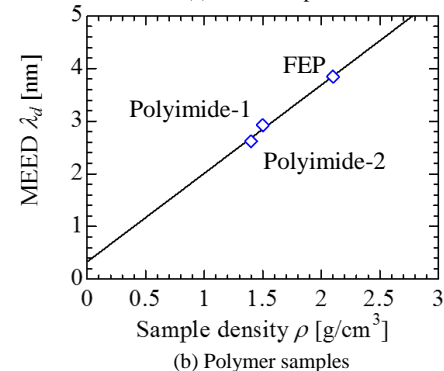


(b) Polymer samples

Fig. 7. Relationship between sample density ρ and escape probability B .



(a) Metal samples



(b) Polymer samples

Fig. 8. Relationship between sample density ρ and mean electron escape depth (MEED) λ_d .

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